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Supplementary information

Supplementary Figure 1.

SEM images of the ϕ = 800 nm Cu/HEA micropillar with h = 50 nm before (a) and after (b) the uniaxial tests. (c) Cross-sectional STEM image of the micropillar. (d) Plastic strain for each constituent layer along the load axis (the red solid line in c) as a function of the number of layers.

